

**Search Notes**

Application/Control No.

10/823,613

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under  
Reexamination

WILES ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	308	12/19/2005	HN
330	86	12/19/2005	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
U.S-PGPUB.		12/19/2005	HN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST UPDATE SEARCH	12/19/2005	HN